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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	598
Number of Logic Elements/Cells	5980
Total RAM Bits	92160
Number of I/O	185
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	240-BFQFP
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c6q240i7

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Table 1–1. Cyclone Device Features (Part 2 of 2)										
Feature	EP1C3	EP1C4	EP1C6	EP1C12	EP1C20					
Total RAM bits	59,904	78,336	92,160	239,616	294,912					
PLLs	1	2	2	2	2					
Maximum user I/O pins (1)	104	301	185	249	301					

Note to Table 1–1:

(1) This parameter includes global clock pins.

Cyclone devices are available in quad flat pack (QFP) and space-saving FineLine[®] BGA packages (see Tables 1–2 through 1–3).

Table 1-2. (Table 1–2. Cyclone Package Options and I/O Pin Counts										
Device	100-Pin TQFP (1)	144-Pin TQFP (1), (2)	240-Pin PQFP (1)	256-Pin FineLine BGA	324-Pin FineLine BGA	400-Pin FineLine BGA					
EP1C3	65	104	_	_	_	_					
EP1C4	_	_	_	_	249	301					
EP1C6	_	98	185	185	_	_					
EP1C12	_	_	173	185	249	_					
EP1C20	_	_	_	_	233	301					

Notes to Table 1–2:

- (1) TQFP: thin quad flat pack. PQFP: plastic quad flat pack.
- (2) Cyclone devices support vertical migration within the same package (i.e., designers can migrate between the EP1C3 device in the 144-pin TQFP package and the EP1C6 device in the same package).

Vertical migration means you can migrate a design from one device to another that has the same dedicated pins, JTAG pins, and power pins, and are subsets or supersets for a given package across device densities. The largest density in any package has the highest number of power pins; you must use the layout for the largest planned density in a package to provide the necessary power pins for migration.

For I/O pin migration across densities, cross-reference the available I/O pins using the device pin-outs for all planned densities of a given package type to identify which I/O pins can be migrated. The Quartus® II software can automatically cross-reference and place all pins for you when given a device migration list. If one device has power or ground pins, but these same pins are user I/O on a different device that is in the migration path,the Quartus II software ensures the pins are not used as user I/O in the Quartus II software. Ensure that these pins are connected

Logic Array Blocks

Each LAB consists of 10 LEs, LE carry chains, LAB control signals, a local interconnect, look-up table (LUT) chain, and register chain connection lines. The local interconnect transfers signals between LEs in the same LAB. LUT chain connections transfer the output of one LE's LUT to the adjacent LE for fast sequential LUT connections within the same LAB. Register chain connections transfer the output of one LE's register to the adjacent LE's register within a LAB. The Quartus® II Compiler places associated logic within a LAB or adjacent LABs, allowing the use of local, LUT chain, and register chain connections for performance and area efficiency. Figure 2–2 details the Cyclone LAB.

Row Interconnect Column Interconnect Direct link interconnect from Direct link adjacent block interconnect from adjacent block Direct link Direct link interconnect to interconnect to adjacent block adjacent block LÄB Local Interconnect

Figure 2-2. Cyclone LAB Structure

LAB Interconnects

The LAB local interconnect can drive LEs within the same LAB. The LAB local interconnect is driven by column and row interconnects and LE outputs within the same LAB. Neighboring LABs, PLLs, and M4K RAM blocks from the left and right can also drive a LAB's local interconnect through the direct link connection. The direct link connection feature minimizes the use of row and column interconnects, providing higher

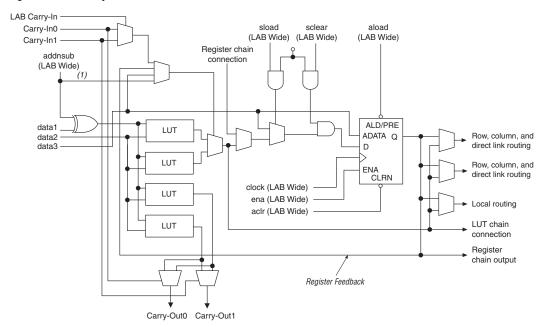


Figure 2-7. LE in Dynamic Arithmetic Mode

Note to Figure 2-7:

(1) The addnsub signal is tied to the carry input for the first LE of a carry chain only.

Carry-Select Chain

The carry-select chain provides a very fast carry-select function between LEs in dynamic arithmetic mode. The carry-select chain uses the redundant carry calculation to increase the speed of carry functions. The LE is configured to calculate outputs for a possible carry-in of 0 and carry-in of 1 in parallel. The carry-in0 and carry-in1 signals from a lower-order bit feed forward into the higher-order bit via the parallel carry chain and feed into both the LUT and the next portion of the carry chain. Carry-select chains can begin in any LE within a LAB.

The speed advantage of the carry-select chain is in the parallel pre-computation of carry chains. Since the LAB carry-in selects the precomputed carry chain, not every LE is in the critical path. Only the propagation delays between LAB carry-in generation (LE 5 and LE 10) are now part of the critical path. This feature allows the Cyclone architecture to implement high-speed counters, adders, multipliers, parity functions, and comparators of arbitrary width.

migrating through different device densities. Dedicated row interconnects route signals to and from LABs, PLLs, and M4K memory blocks within the same row. These row resources include:

- Direct link interconnects between LABs and adjacent blocks
- R4 interconnects traversing four blocks to the right or left

The direct link interconnect allows a LAB or M4K memory block to drive into the local interconnect of its left and right neighbors. Only one side of a PLL block interfaces with direct link and row interconnects. The direct link interconnect provides fast communication between adjacent LABs and/or blocks without using row interconnect resources.

The R4 interconnects span four LABs, or two LABs and one M4K RAM block. These resources are used for fast row connections in a four-LAB region. Every LAB has its own set of R4 interconnects to drive either left or right. Figure 2–9 shows R4 interconnect connections from a LAB. R4 interconnects can drive and be driven by M4K memory blocks, PLLs, and row IOEs. For LAB interfacing, a primary LAB or LAB neighbor can drive a given R4 interconnect. For R4 interconnects that drive to the right, the primary LAB and right neighbor can drive on to the interconnect. For R4 interconnects that drive to the left, the primary LAB and its left neighbor can drive on to the interconnect. R4 interconnects can drive other R4 interconnects to extend the range of LABs they can drive. R4 interconnects can also drive C4 interconnects for connections from one row to another.

register outputs (number of taps $n \times$ width w) must be less than the maximum data width of the M4K RAM block (×36). To create larger shift registers, multiple memory blocks are cascaded together.

Data is written into each address location at the falling edge of the clock and read from the address at the rising edge of the clock. The shift register mode logic automatically controls the positive and negative edge clocking to shift the data in one clock cycle. Figure 2–14 shows the M4K memory block in the shift register mode.

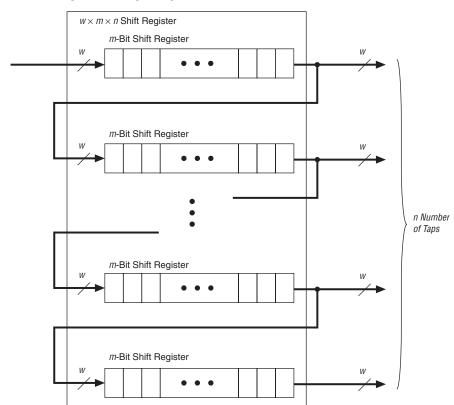


Figure 2-14. Shift Register Memory Configuration

Memory Configuration Sizes

The memory address depths and output widths can be configured as $4,096 \times 1, 2,048 \times 2, 1,024 \times 4,512 \times 8$ (or 512×9 bits), 256×16 (or 256×18 bits), and 128×32 (or 128×36 bits). The 128×32 - or 36-bit configuration

Figure 2-15. M4K RAM Block Control Signals

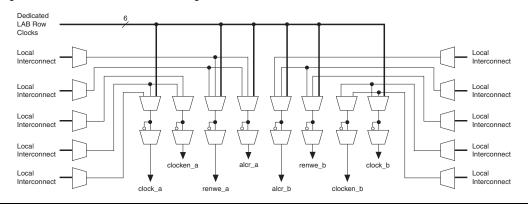
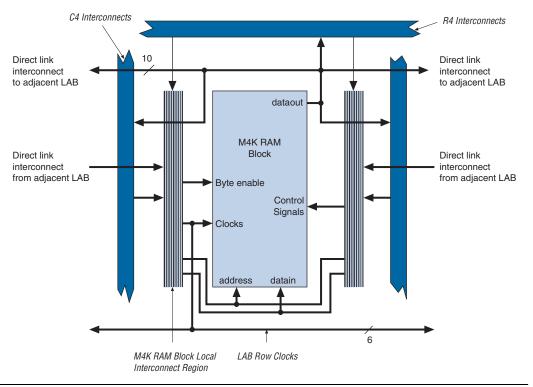


Figure 2-16. M4K RAM Block LAB Row Interface



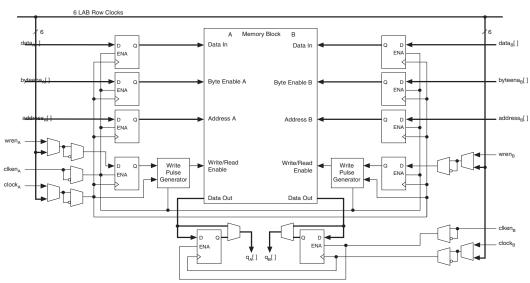


Figure 2–18. Input/Output Clock Mode in True Dual-Port Mode Notes (1), (2)

Notes to Figure 2–18:

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Read/Write Clock Mode

The M4K memory blocks implement read/write clock mode for simple dual-port memory. You can use up to two clocks in this mode. The write clock controls the block's data inputs, wraddress, and wren. The read clock controls the data output, rdaddress, and rden. The memory blocks support independent clock enables for each clock and asynchronous clear signals for the read- and write-side registers. Figure 2–20 shows a memory block in read/write clock mode.

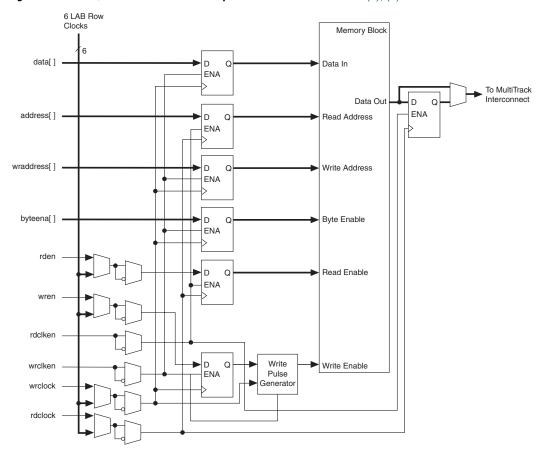


Figure 2–20. Read/Write Clock Mode in Simple Dual-Port Mode Notes (1), (2)

Notes to Figure 2–20:

- (1) All registers shown except the rden register have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Programmable Duty Cycle

The programmable duty cycle allows PLLs to generate clock outputs with a variable duty cycle. This feature is supported on each PLL post-scale counter (g0, g1, e). The duty cycle setting is achieved by a low- and high-time count setting for the post-scale dividers. The Quartus II software uses the frequency input and the required multiply or divide rate to determine the duty cycle choices.

Control Signals

There are three control signals for clearing and enabling PLLs and their outputs. You can use these signals to control PLL resynchronization and the ability to gate PLL output clocks for low-power applications.

The pllenable signal enables and disables PLLs. When the pllenable signal is low, the clock output ports are driven by ground and all the PLLs go out of lock. When the pllenable signal goes high again, the PLLs relock and resynchronize to the input clocks. An input pin or LE output can drive the pllenable signal.

The areset signals are reset/resynchronization inputs for each PLL. Cyclone devices can drive these input signals from input pins or from LEs. When areset is driven high, the PLL counters will reset, clearing the PLL output and placing the PLL out of lock. When driven low again, the PLL will resynchronize to its input as it relocks.

The pfdena signals control the phase frequency detector (PFD) output with a programmable gate. If you disable the PFD, the VCO will operate at its last set value of control voltage and frequency with some drift, and the system will continue running when the PLL goes out of lock or the input clock disables. By maintaining the last locked frequency, the system has time to store its current settings before shutting down. You can either use their own control signal or gated locked status signals to trigger the pfdena signal.



For more information about Cyclone PLLs, refer to *Using PLLs in Cyclone Devices* chapter in the *Cyclone Device Handbook*.

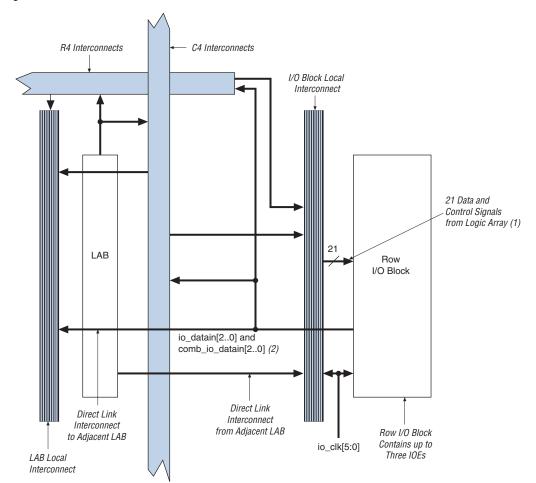


Figure 2-28. Row I/O Block Connection to the Interconnect

Notes to Figure 2–28:

- (1) The 21 data and control signals consist of three data out lines, io_dataout[2..0], three output enables, io_coe[2..0], three input clock enables, io_cce_in[2..0], three output clock enables, io_cce_out[2..0], three clocks, io_cclk[2..0], three asynchronous clear signals, io_caclr[2..0], and three synchronous clear signals, io_csclr[2..0].
- (2) Each of the three IOEs in the row I/O block can have one io_datain input (combinatorial or registered) and one comb_io_datain (combinatorial) input.

Slew-Rate Control

The output buffer for each Cyclone device I/O pin has a programmable output slew-rate control that can be configured for low noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay to rising and falling edges. Each I/O pin has an individual slew-rate control, allowing the designer to specify the slew rate on a pin-by-pin basis. The slew-rate control affects both the rising and falling edges.

Bus Hold

Each Cyclone device I/O pin provides an optional bus-hold feature. The bus-hold circuitry can hold the signal on an I/O pin at its last-driven state. Since the bus-hold feature holds the last-driven state of the pin until the next input signal is present, an external pull-up or pull-down resistor is not necessary to hold a signal level when the bus is tri-stated.

The bus-hold circuitry also pulls undriven pins away from the input threshold voltage where noise can cause unintended high-frequency switching. The designer can select this feature individually for each I/O pin. The bus-hold output will drive no higher than V_{CCIO} to prevent overdriving signals. If the bus-hold feature is enabled, the device cannot use the programmable pull-up option. Disable the bus-hold feature when the I/O pin is configured for differential signals.

The bus-hold circuitry uses a resistor with a nominal resistance (RBH) of approximately 7 k Ω to pull the signal level to the last-driven state. Table 4–15 on page 4–6 gives the specific sustaining current for each V_{CCIO} voltage level driven through this resistor and overdrive current used to identify the next-driven input level.

The bus-hold circuitry is only active after configuration. When going into user mode, the bus-hold circuit captures the value on the pin present at the end of configuration.

Programmable Pull-Up Resistor

Each Cyclone device I/O pin provides an optional programmable pull-up resistor during user mode. If the designer enables this feature for an I/O pin, the pull-up resistor (typically 25 k Ω) holds the output to the V_{CCIO} level of the output pin's bank. Dedicated clock pins do not have the optional programmable pull-up resistor.

The Cyclone $V_{\rm CCINT}$ pins must always be connected to a 1.5-V power supply. If the $V_{\rm CCINT}$ level is 1.5 V, then input pins are 1.5-V, 1.8-V, 2.5-V, and 3.3-V tolerant. The $V_{\rm CCIO}$ pins can be connected to either a 1.5-V, 1.8-V, 2.5-V, or 3.3-V power supply, depending on the output requirements. The output levels are compatible with systems of the same voltage as the power supply (i.e., when $V_{\rm CCIO}$ pins are connected to a 1.5-V power supply, the output levels are compatible with 1.5-V systems). When $V_{\rm CCIO}$ pins are connected to a 3.3-V power supply, the output high is 3.3-V and is compatible with 3.3-V or 5.0-V systems. Table 2–14 summarizes Cyclone MultiVolt I/O support.

Table 2–14. Cyclone MultiVolt I/O Support Note (1)										
V (V)		Ir	nput Sign	al			0ι	ıtput Sigr	nal	
V _{CCIO} (V)	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V
1.5	✓	✓	√ (2)	√ (2)	_	✓	_	_	_	_
1.8	✓	✓	√ (2)	√ (2)	_	√ (3)	✓	_	_	_
2.5	_	_	✓	✓	_	√ (5)	√ (5)	✓	_	_
3.3	_	_	√ (4)	✓	√ (6)	√ (7)	√ (7)	√ (7)	✓	√ (8)

Notes to Table 2-14:

- (1) The PCI clamping diode must be disabled to drive an input with voltages higher than V_{CCIO}.
- (2) When V_{CCIO} = 1.5-V or 1.8-V and a 2.5-V or 3.3-V input signal feeds an input pin, higher pin leakage current is expected. Turn on Allow voltage overdrive for LVTTL / LVCMOS input pins in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combinations.
- (3) When $V_{CCIO} = 1.8$ -V, a Cyclone device can drive a 1.5-V device with 1.8-V tolerant inputs.
- (4) When $V_{CCIO} = 3.3$ -V and a 2.5-V input signal feeds an input pin, the V_{CCIO} supply current will be slightly larger than expected.
- (5) When V_{CCIO} = 2.5-V, a Cyclone device can drive a 1.5-V or 1.8-V device with 2.5-V tolerant inputs.
- (6) Cyclone devices can be 5.0-V tolerant with the use of an external resistor and the internal PCI clamp diode.
- (7) When V_{CCIO} = 3.3-V, a Cyclone device can drive a 1.5-V, 1.8-V, or 2.5-V device with 3.3-V tolerant inputs.
- (8) When $V_{CCIO} = 3.3$ -V, a Cyclone device can drive a device with 5.0-V LVTTL inputs but not 5.0-V LVCMOS inputs.

Power Sequencing and Hot Socketing

Because Cyclone devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. Therefore, the V_{CCIO} and V_{CCINT} power supplies may be powered in any order.

Signals can be driven into Cyclone devices before and during power up without damaging the device. In addition, Cyclone devices do not drive out during power up. Once operating conditions are reached and the device is configured, Cyclone devices operate as specified by the user.

The Cyclone device instruction register length is 10 bits and the USERCODE register length is 32 bits. Tables 3–2 and 3–3 show the boundary-scan register length and device IDCODE information for Cyclone devices.

Table 3–2. Cyclone Boundary-Scan Register Length						
Device Boundary-Scan Register Lengt						
EP1C3	339					
EP1C4	930					
EP1C6	582					
EP1C12	774					
EP1C20	930					

Table 3–3	Table 3–3. 32-Bit Cyclone Device IDCODE									
		IDCODE (32 bit	s) (1)							
Device	Version (4 Bits)	Part Number (16 Bits)	Manufacturer Identity (11 Bits)	LSB (1 Bit) (2)						
EP1C3	0000	0010 0000 1000 0001	000 0110 1110	1						
EP1C4	0000	0010 0000 1000 0101	000 0110 1110	1						
EP1C6	0000	0010 0000 1000 0010	000 0110 1110	1						
EP1C12	0000	0010 0000 1000 0011	000 0110 1110	1						
EP1C20	0000	0010 0000 1000 0100	000 0110 1110	1						

Notes to Table 3-3:

- (1) The most significant bit (MSB) is on the left.
- (2) The IDCODE's least significant bit (LSB) is always 1.



4. DC and Switching Characteristics

C51004-1.7

Operating Conditions

Cyclone® devices are offered in both commercial, industrial, and extended temperature grades. However, industrial-grade and extended-temperature-grade devices may have limited speed-grade availability.

Tables 4–1 through 4–16 provide information on absolute maximum ratings, recommended operating conditions, DC operating conditions, and capacitance for Cyclone devices.

Table 4-1	Table 4–1. Cyclone Device Absolute Maximum Ratings Notes (1), (2)										
Symbol	Parameter	Conditions	Minimum	Maximum	Unit						
V _{CCINT}	Supply voltage	With respect to ground (3)	-0.5	2.4	V						
V _{CCIO}			-0.5	4.6	V						
V _{CCA}	Supply voltage	With respect to ground (3)	-0.5	2.4	V						
Vı	DC input voltage		-0.5	4.6	V						
I _{OUT}	DC output current, per pin		-25	25	mA						
T _{STG}	Storage temperature	No bias	-65	150	°C						
T _{AMB}	Ambient temperature	Under bias	-65	135	°C						
T _J	Junction temperature	BGA packages under bias	_	135	°C						

Table 4–2. Cyclone Device Recommended Operating Conditions (Part 1 of 2)									
Symbol	Parameter	Conditions	Minimum	Maximum	Unit				
V _{CCINT}	Supply voltage for internal logic and input buffers	(4)	1.425	1.575	V				
V _{CCIO}	Supply voltage for output buffers, 3.3-V operation	(4)	3.00	3.60	V				
	Supply voltage for output buffers, 2.5-V operation	(4)	2.375	2.625	V				
	Supply voltage for output buffers, 1.8-V operation	(4)	1.71	1.89	V				
	Supply voltage for output buffers, 1.5-V operation	(4)	1.4	1.6	V				
V _I	Input voltage	(3), (5)	-0.5	4.1	V				

Table 4–10.	Table 4–10. 3.3-V PCI Specifications (Part 2 of 2)										
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit					
V _{OH}	High-level output voltage	I _{OUT} = -500 μA	$0.9 \times V_{CCIO}$	_	_	V					
V _{OL}	Low-level output voltage	I _{OUT} = 1,500 μA	_	_	0.1 × V _{CCIO}	V					

Table 4–11	Table 4–11. SSTL-2 Class I Specifications									
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit				
V _{CCIO}	Output supply voltage	_	2.375	2.5	2.625	V				
V _{TT}	Termination voltage	_	V _{REF} - 0.04	V_{REF}	V _{REF} + 0.04	V				
V _{REF}	Reference voltage	_	1.15	1.25	1.35	V				
V _{IH}	High-level input voltage	_	V _{REF} + 0.18	_	3.0	V				
V _{IL}	Low-level input voltage	_	-0.3	_	V _{REF} - 0.18	V				
V _{OH}	High-level output voltage	I _{OH} = -8.1 mA (11)	V _{TT} + 0.57	_	_	V				
V _{OL}	Low-level output voltage	I _{OL} = 8.1 mA (11)	_	_	V _{TT} – 0.57	V				

Table 4-12	Table 4–12. SSTL-2 Class II Specifications									
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit				
V _{CCIO}	Output supply voltage	_	2.3	2.5	2.7	V				
V _{TT}	Termination voltage	_	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04	V				
V_{REF}	Reference voltage	_	1.15	1.25	1.35	٧				
V _{IH}	High-level input voltage	_	V _{REF} + 0.18	_	V _{CCIO} + 0.3	V				
V _{IL}	Low-level input voltage	_	-0.3	_	V _{REF} - 0.18	٧				
V _{OH}	High-level output voltage	$I_{OH} = -16.4 \text{ mA}$ (11)	V _{TT} + 0.76	_	_	٧				
V _{OL}	Low-level output voltage	I _{OL} = 16.4 mA (11)	_	_	V _{TT} – 0.76	V				

Table 4-13	Table 4–13. SSTL-3 Class I Specifications (Part 1 of 2)										
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit					
V _{CCIO}	Output supply voltage	_	3.0	3.3	3.6	V					
V_{TT}	Termination voltage	_	V _{REF} - 0.05	V_{REF}	V _{REF} + 0.05	V					

Table 4–16. Cyclone Device Capacitance Note (14)										
Symbol	Parameter	Typical	Unit							
C _{IO}	Input capacitance for user I/O pin	4.0	pF							
C _{LVDS}	Input capacitance for dual-purpose LVDS/user I/O pin	4.7	pF							
C _{VREF}	Input capacitance for dual-purpose V _{REF} /user I/O pin.	12.0	pF							
C _{DPCLK}	Input capacitance for dual-purpose DPCLK/user I/O pin.	4.4	pF							
C _{CLK}	Input capacitance for CLK pin.	4.7	pF							

Notes to Tables 4–1 through 4–16:

- (1) Refer to the Operating Requirements for Altera Devices Data Sheet.
- (2) Conditions beyond those listed in Table 4–1 may cause permanent damage to a device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse affects on the device.
- (3) Minimum DC input is -0.5 V. During transitions, the inputs may undershoot to -2.0 V or overshoot to 4.6 V for input currents less than 100 mA and periods shorter than 20 ns.
- (4) Maximum V_{CC} rise time is 100 ms, and V_{CC} must rise monotonically.
- (5) All pins, including dedicated inputs, clock, I/O, and JTAG pins, may be driven before V_{CCINT} and V_{CCIO} are powered.
- (6) Typical values are for $T_A = 25^{\circ}$ C, $V_{CCINT} = 1.5$ V, and $V_{CCIO} = 1.5$ V, 1.8 V, 2.5 V, and 3.3 V.
- (7) V_I = ground, no load, no toggling inputs.
- (8) This value is specified for normal device operation. The value may vary during power-up. This applies for all V_{CCIO} settings (3.3, 2.5, 1.8, and 1.5 V).
- (9) R_{CONF} is the measured value of internal pull-up resistance when the I/O pin is tied directly to GND. R_{CONF} value will be lower if an external source drives the pin higher than V_{CCIO}.
- (10) Pin pull-up resistance values will lower if an external source drives the pin higher than V_{CCIO}.
- (11) Drive strength is programmable according to values in Cyclone Architecture chapter in the Cyclone Device Handbook.
- (12) Overdrive is possible when a 1.5 V or 1.8 V and a 2.5 V or 3.3 V input signal feeds an input pin. Turn on "Allow voltage overdrive" for LVTTL/LVCMOS input pins in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combination. However, higher leakage current is expected.
- (13) The Cyclone LVDS interface requires a resistor network outside of the transmitter channels.
- (14) Capacitance is sample-tested only. Capacitance is measured using time-domain reflections (TDR). Measurement accuracy is within ±0.5 pF.

Power Consumption

Designers can use the Altera web Early Power Estimator to estimate the device power.

Cyclone devices require a certain amount of power-up current to successfully power up because of the nature of the leading-edge process on which they are fabricated. Table 4–17 shows the maximum power-up current required to power up a Cyclone device.

Table 4–17. Cyclone Maximum Power-Up Current (I _{CCINT}) Requirements (In-Rush Current)										
Device	Unit									
EP1C3	150	180	mA							
EP1C4	150	180	mA							
EP1C6	175	210	mA							
EP1C12	300	360	mA							
EP1C20	500	600	mA							

Notes to Table 4–17:

- The Cyclone devices (except for the EP1C20 device) meet the power up specification for Mini PCI.
- (2) The lot codes 9G0082 to 9G2999, or 9G3109 and later comply to the specifications in Table 4–17 and meet the Mini PCI specification. Lot codes appear at the top of the device.
- (3) The lot codes 9H0004 to 9H29999, or 9H3014 and later comply to the specifications in this table and meet the Mini PCI specification. Lot codes appear at the top of the device.

Designers should select power supplies and regulators that can supply this amount of current when designing with Cyclone devices. This specification is for commercial operating conditions. Measurements were performed with an isolated Cyclone device on the board. Decoupling capacitors were not used in this measurement. To factor in the current for decoupling capacitors, sum up the current for each capacitor using the following equation:

$$I = C (dV/dt)$$

The exact amount of current that is consumed varies according to the process, temperature, and power ramp rate. If the power supply or regulator can supply more current than required, the Cyclone device may consume more current than the maximum current specified in Table 4–17. However, the device does not require any more current to successfully power up than what is listed in Table 4–17.

The duration of the I_{CCINT} power-up requirement depends on the V_{CCINT} voltage supply rise time. The power-up current consumption drops when the V_{CCINT} supply reaches approximately 0.75 V. For example, if the V_{CCINT} rise time has a linear rise of 15 ms, the current consumption spike drops by 7.5 ms.

Performance

The maximum internal logic array clock tree frequency is limited to the specifications shown in Table 4–19.

Table 4–19.	Table 4–19. Clock Tree Maximum Performance Specification											
Parameter	Definition	-6 Speed Grade			-7 Speed Grade			-8 Speed Grade			Units	
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIIIS	
Clock tree f _{MAX}	Maximum frequency that the clock tree can support for clocking registered logic		_	405	_	_	320		_	275	MHz	

Table 4–20 shows the Cyclone device performance for some common designs. All performance values were obtained with the Quartus II software compilation of library of parameterized modules (LPM) functions or megafunctions. These performance values are based on EP1C6 devices in 144-pin TQFP packages.

Table 4-20	Table 4–20. Cyclone Device Performance												
			R	esources U	sed	Performance							
Resource Used	g	Mode	LEs	M4K Memory Bits	M4K Memory Blocks	-6 Speed Grade (MHz)	-7 Speed Grade (MHz)	-8 Speed Grade (MHz)					
LE	16-to-1 multiplexer	_	21	_	_	405.00	320.00	275.00					
	32-to-1 multiplexer	_	44	_	_	317.36	284.98	260.15					
	16-bit counter	_	16	_	_	405.00	320.00	275.00					
	64-bit counter (1)	_	66	_	_	208.99	181.98	160.75					

Table 4–40. Cyclone I/O Standard Column Pin Input Delay Adders (Part 2 of 2)											
I/O Standard	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	Hnit					
	Min	Max	Min	Max	Min	Max	Unit				
SSTL-2 class II		-278	_	-320	_	-362	ps				
LVDS		-261	_	-301	_	-340	ps				

Table 4–41. Cyclone I/O Standard Row Pin Input Delay Adders											
I/O Standard	-6 Speed Grade		-7 Spee	ed Grade	-8 Spee	lla:4					
	Min	Max	Min	Max	Min	Max	Unit				
LVCMOS	_	0	_	0	_	0	ps				
3.3-V LVTTL	_	0	_	0	_	0	ps				
2.5-V LVTTL	_	27	_	31	_	35	ps				
1.8-V LVTTL	_	182	_	209	_	236	ps				
1.5-V LVTTL	_	278	_	319	_	361	ps				
3.3-V PCI (1)	_	0	_	0	_	0	ps				
SSTL-3 class I	_	-250	_	-288	_	-325	ps				
SSTL-3 class II	_	-250	_	-288	_	-325	ps				
SSTL-2 class I	_	-278	_	-320	_	-362	ps				
SSTL-2 class II	_	-278	_	-320	_	-362	ps				
LVDS	_	-261	_	-301	_	-340	ps				

Standard		-6 Spee	d Grade	-7 Spe	ed Grade	-8 Spe	ed Grade	
Stallt	iaru	Min	Max	Min	Max	Min	Max	Unit
LVCMOS	2 mA	_	0	_	0	_	0	ps
	4 mA	_	-489	_	-563	_	-636	ps
	8 mA	_	-855	_	-984	_	-1,112	ps
	12 mA	_	-993	_	-1,142	_	-1,291	ps
3.3-V LVTTL	4 mA	_	0	_	0	_	0	ps
	8 mA	_	-347	_	-400	_	-452	ps
	12 mA	_	-858	_	-987	_	-1,116	ps
	16 mA	_	-819	_	-942	_	-1,065	ps
	24 mA	_	-993	_	-1,142	_	-1,291	ps

Table 4-44. 0	Table 4–44. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Column Pins (Part 2 of 2)											
I/O Standard		-6 Speed Grade		-7 Spee	d Grade	-8 Spee	1114					
i/U Star	iuaru	Min	Max	Min	Max	Min	Max	Unit				
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps				
	4 mA	_	5,109	_	5,875	_	6,641	ps				
	8 mA	_	4,793	_	5,511	_	6,230	ps				
SSTL-3 class I		_	1,390	_	1,598	_	1,807	ps				
SSTL-3 class I	I	_	989	_	1,137	_	1,285	ps				
SSTL-2 class I		_	1,965	_	2,259	_	2,554	ps				
SSTL-2 class I	I	_	1,692	_	1,945		2,199	ps				
LVDS	·	_	802	_	922	_	1,042	ps				

		-6 Snor	ad Grado	-7 Sno	ed Grade	-8 Sno	ed Grade	
I/O Standard		-6 Speed Grade		-/ Spec	tu ulaut	-o she	Unit	
·		Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA	_	1,800	_	2,070	_	2,340	ps
	4 mA	_	1,311	_	1,507	_	1,704	ps
	8 mA	_	945	_	1,086	_	1,228	ps
	12 mA	_	807	_	928	_	1,049	ps
3.3-V LVTTL	4 mA	_	1,831	_	2,105	_	2,380	ps
	8 mA	_	1,484	_	1,705	_	1,928	ps
	12 mA	_	973	_	1,118	_	1,264	ps
	16 mA	_	1,012	_	1,163	_	1,315	ps
	24 mA	_	838	_	963	_	1,089	ps
2.5-V LVTTL	2 mA	_	2,747	_	3,158	_	3,570	ps
	8 mA	_	1,757	_	2,019	_	2,283	ps
	12 mA	_	1,763	_	2,026	_	2,291	ps
	16 mA	_	1,623	_	1,865	_	2,109	ps
1.8-V LVTTL	2 mA	_	5,506	_	6,331	_	7,157	ps
	8 mA	_	4,220	_	4,852	_	5,485	ps
	12 mA	_	4,008	_	4,608	_	5,209	ps
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps
	4 mA	_	5,109	_	5,875	_	6,641	ps
	8 mA	_	4,793	_	5,511	_	6,230	ps
3.3-V PCI		_	923	_	1,061	_	1,199	ps